

Supplementary Information

In situ Determination of K, Ca, S and Si in Fresh Sugar Cane Leaves by Handheld Energy Dispersive X-Ray Fluorescence Spectrometry

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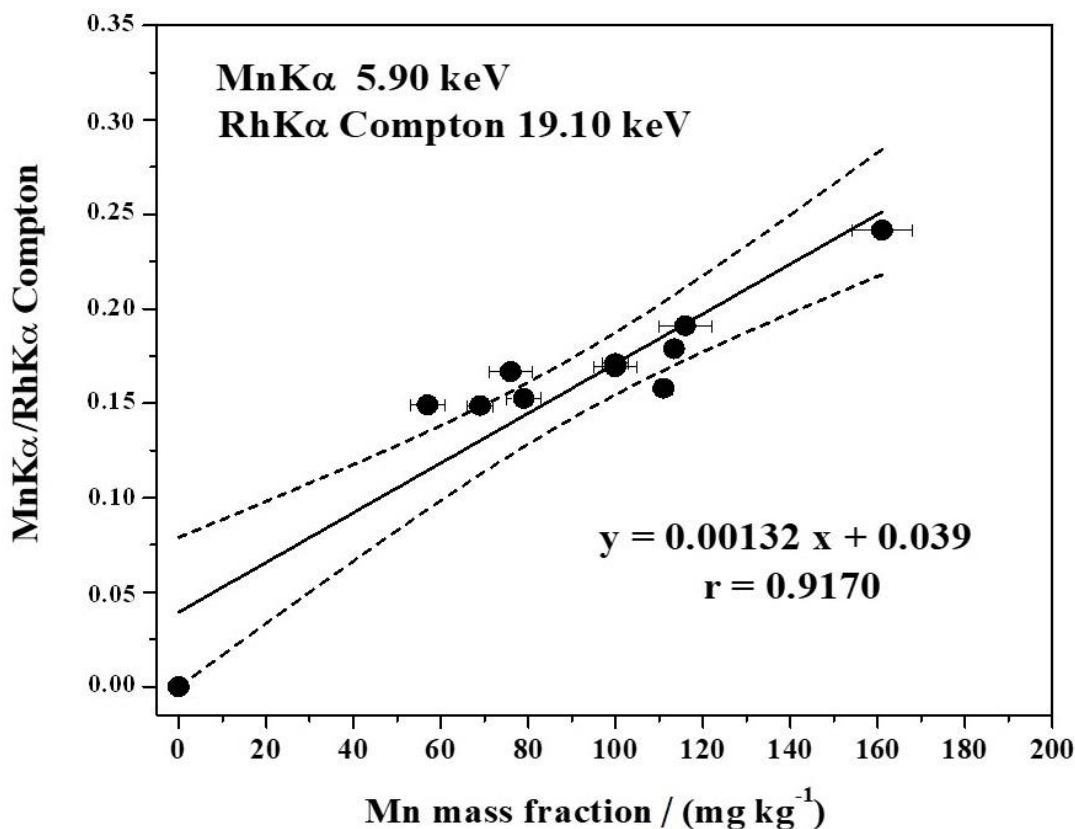


Figure S1. Analytical curve for Mn K α 5.90 keV, obtained from the *in situ* analysis of fresh sugar cane leaves by a handheld EDXRF spectrometer. The Mn K α emission line intensities were corrected by the scattering radiation method using the Rh K α Compton peak at 19.10 keV. Dotted lines represent 95 % confidence bands.

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